

**IN THE ABSTRACT OF THE DISCLOSURE**

Please find attached, on a separate sheet, a rewritten  
Abstract of the Disclosure.

## ABSTRACT OF THE DISCLOSURE

There is provided an apparatus and a method for automatically generating patterns including a pattern applied for a path that influences crosstalk to a measurement path, in a delay test using a scan path to make measurement of the effect of the path that influences crosstalk to the measurement path possible. An adjacent path extraction process ~~102~~ is performed on the basis of layout information on a semiconductor integrated circuit so as to extract information on a path that influences crosstalk, with reference to crosstalk information, a measurement path extraction process ~~(106)~~ is performed, so that information on an aggressor path that influences crosstalk to the measurement path of a combinational circuit between flip-flops that constitutes the scan path is generated, and then, on the basis of circuit information ~~(108)~~, and information ~~(107)~~ on the measurement path and the aggressor path, and a Delay\_test ATG ~~(109)~~ generates delay test ~~patterns (110)~~, ~~including a pattern for outputting a signal for measuring a delay from a flip flop associated with the measurement path and a pattern for outputting a signal that influence crosstalk to the measurement path from a flip flop associated with the aggressor path.~~ patterns.